



Recent Results with the Backward EMC Prototype

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PANDA LVIII Collaboration Meeting

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- 4 Lowest Single Channel Threshold
- 5 Angle Scan



Prototype “Proto16”

Backward EMC Prototype “Proto16”

PROTO16

■ Mechanics

- Carbon fibre alveole with 16 $PbWO_4$ crystals
- Two mounting plates separated with glass fibre feet
- optical fibre to every crystal

■ Cooling

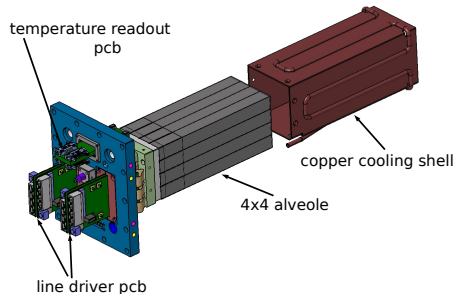
- Cooling shell
- Insulated with VIP
- Nitrogen supply

■ Monitoring

- Flat thermal sensors
- THMP

■ Readout

- Two APD per crystal
- APFEL ASIC
- Line driver





Upgrades of Proto16

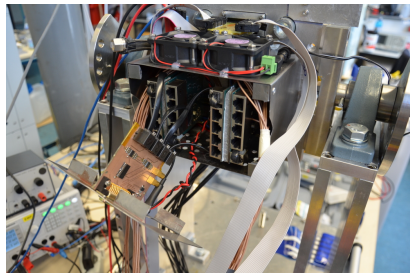
- Used optical grease between APD and crystals
- Shielding for the distribution (sender) boards
- Receiver boards replaced by passive adapters
- Embedding of PANDA (Uppsala) ADC and TRB readout



Shielding

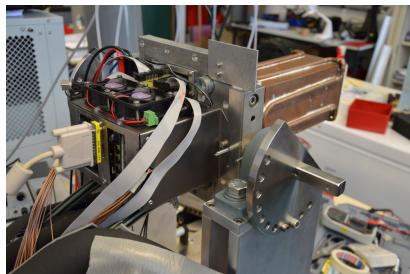
Provides

- Power supply for ASIC and line drivers
- Shielding for ASIC programming cables
- Ventilation

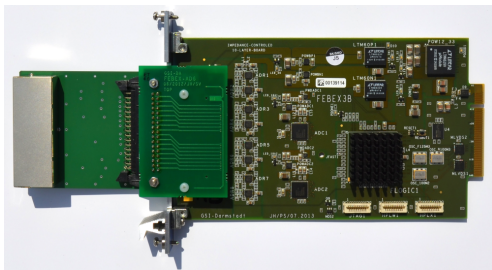


Open issue

- Shielding for Pt100 sensor cables
- Had to be unplugged during beam test



New “Receiver” Boards



- General passive adapter RJ45 to pin header connector
- Used with the Febex sampling ADC
- Possibility for voltage divider to attenuate signals



APD Characteristics

APD characteristics

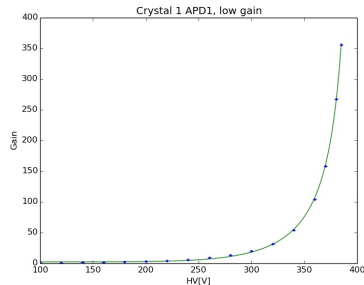
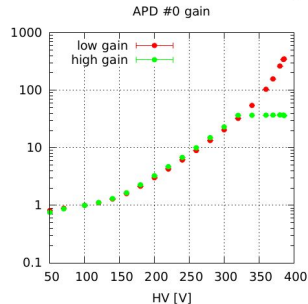
- Measured with the Proto16:
LED pulses through optical fibres
- Last time: changing light intensity
Now: only one intensity for all voltages
- Normalising at $U = 100$ V
- Fit function:

$$M = \frac{A}{1 - (U/U_{br.})^k} + C$$

- Calculate U for every single APD for given M

Two Gains for Beamtime

- $G = 150$: $\frac{1}{G} \frac{\partial G}{\partial U} = 5 \frac{\%}{V}$ **L**
- $G = 400$: $\frac{1}{G} \frac{\partial G}{\partial U} = 10 \frac{\%}{V}$ **H**

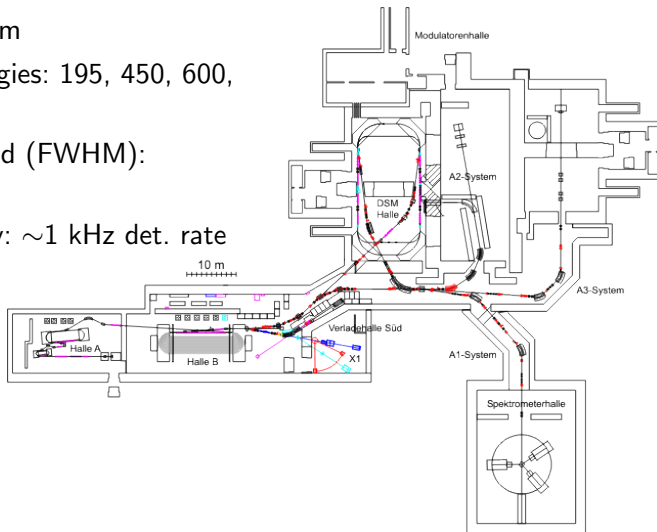




Beamtime Mai 2016

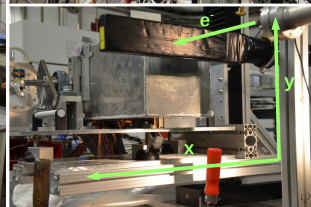
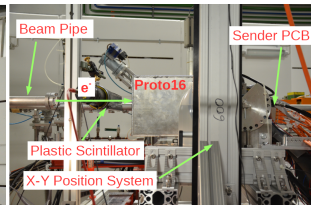
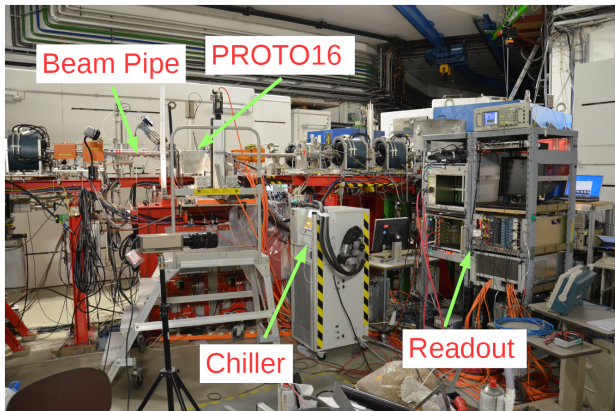
Beam test May 2016 at MAMI

- About 50 hours: 27.5–30.5
- Electron beam
- 4 beam energies: 195, 450, 600, 855 MeV
- Energy spread (FWHM): 100 keV
- Low intensity: ~ 1 kHz det. rate



Test setup

- XY-table for centering each crystal on beam
- Rotatable plate for incidence angle scan
- Plastic scintillator for coincidence event triggering



Measurements

For each beam energy → this talk!

- Each crystal centered on beam
- Two APD gains: **L** and **H**

Position scan

- At 195 MeV and 600 MeV

Angle scan → this talk!

- At 600 MeV

PANDA ADC

- Energies: 195, 450, 600 MeV



Lowest Single Channel Threshold

Threshold Challenge for BVEC

Only one ASIC amplification for BVEC

- Find proper parameters to achieve:
 - No saturation at high energies ~ 1 GeV
 - Lowest single channel threshold of ~ 2 MeV
- Possible “adjusting screws”:
 - ASIC **L** and **H**
 - ASIC amplification factor 10x and 20x
 - APD **L** and **H**
 - FEE attenuation or amplification

Have a look on different combinations:

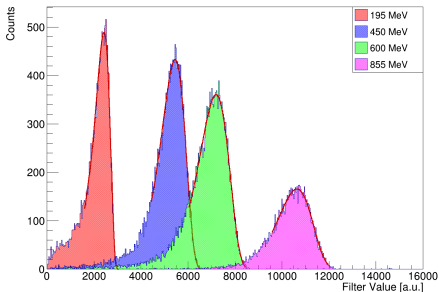
APD	ASIC	
L	L	to small
L	H	interesting
H	L	interesting
H	H	way to big

Threshold Scan - Single Channel Spectra

- Central crystal
- Value = $\frac{1}{2} \sum APD_i$
- **LL** to small (1/16 ADC range)
- **HH** way to big

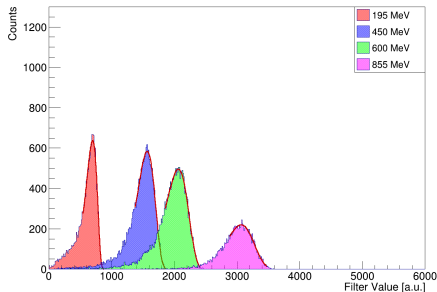
LH - full ADC range

Sum of APD0 & APD1, Central Crystal 11



HL - 1/4 ADC range

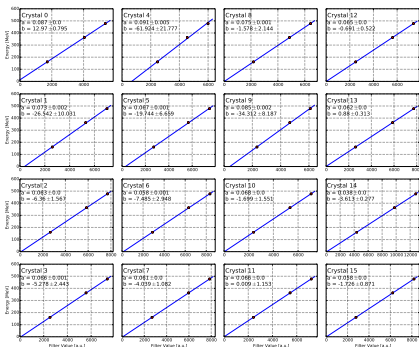
Sum of APD0 & APD1, Central Crystal 11



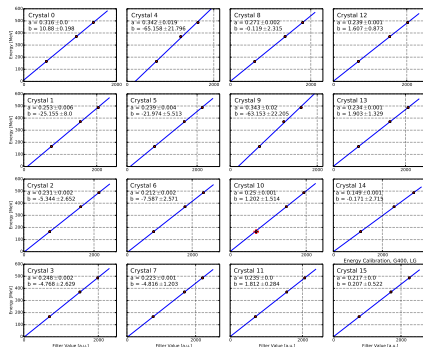
Threshold Scan - Energy Calibration

- Using central crystal data
- 195, 450, 600 MeV
- Deposited energy correction (beam data)

LH - Energy Calibration

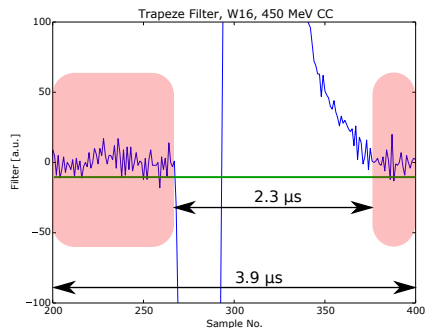
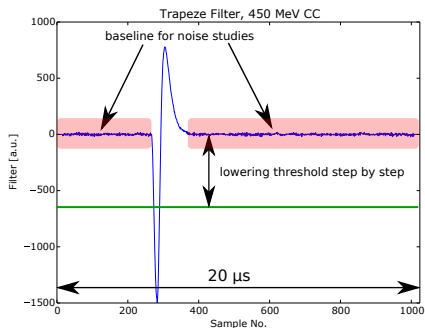


HL - Energy Calibration

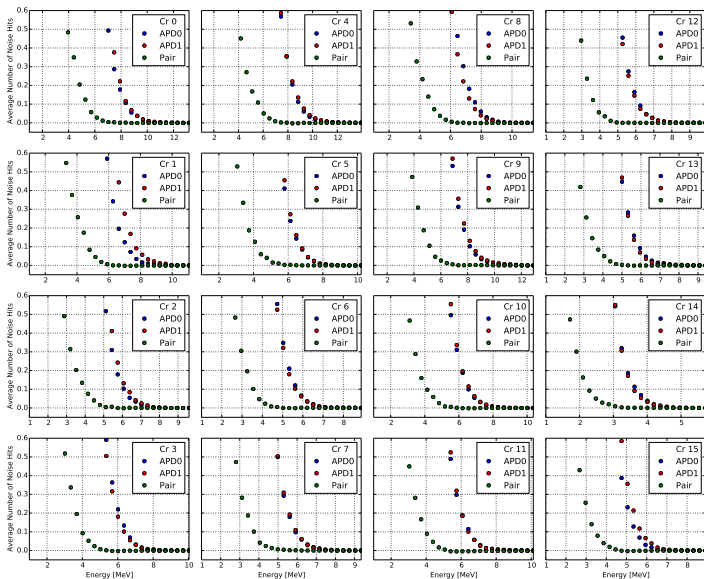


Threshold Scan - Method

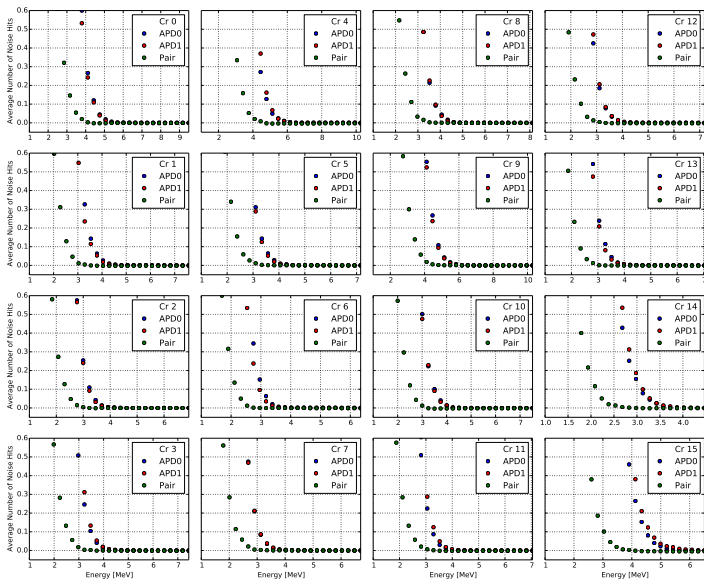
- Using filtered traces
- Lowering threshold step by step
- Count number of hits on trace at a given threshold
- Average of 1390 events (traces)



Threshold Scan - LH



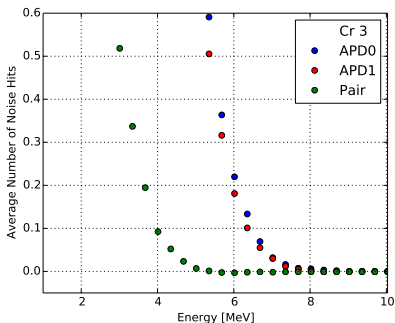
Threshold Scan - HL



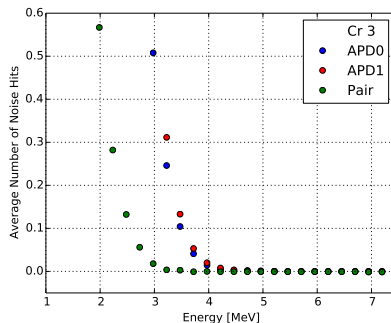
Threshold Scan - Conclusion

- Noise/signal ratio better at high APD gain
- Still some headroom until access noise
- Possible way to go:
 - Set APD gain $\rightarrow$ 2 MeV threshold
 - Attenuate/amplify at FEE level $\rightarrow$ exploit ADC range

LH $\sim$ 5 MeV Threshold



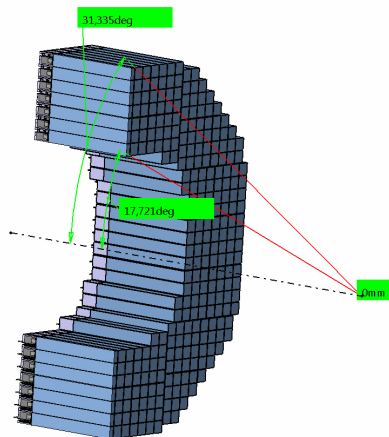
HL $\sim$ 3.5 MeV Threshold



Angle Scan

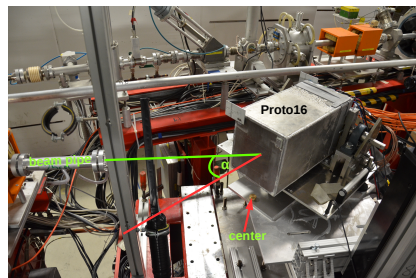
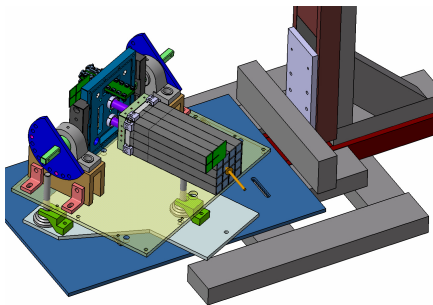
Angle Challenge for BVEC

- BVEC crystals not aligned with scattering angle
- Incidence angle between 17° and 32°
- Influence on energy resolution?



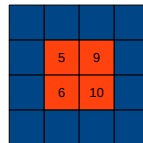
Angle Scan - Positioning System Update

- Add rotation axis to Proto16 X-Y table
- Coordinate transformation $\rightarrow$ center of projection
- Data for 0° , 15° , 25° and 35° at 600 MeV

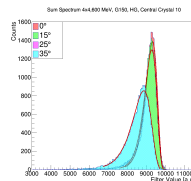
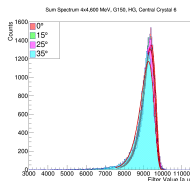
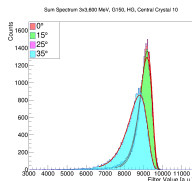
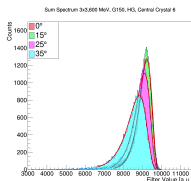
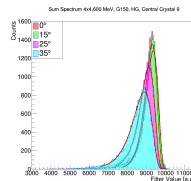
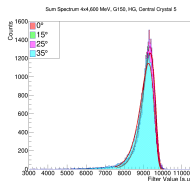
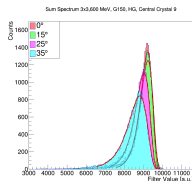
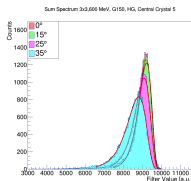


Angle Scan - Comparing 3x3- and 4x4-Matrix

- Losing deposited energy in 3x3 matrix
 - No problem if there are enough neighbouring crystals
- 3x3 matrix - sum spectra



4x4 matrix - sum spectra

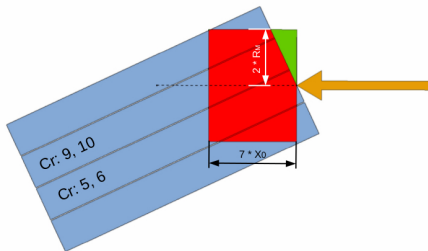


Angle Scan - Comparing 3x3- and 4x4-Matrix

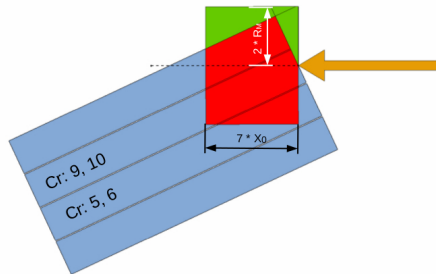
- The smaller the angel the better
- The more surrounding crystals the better

		5	9	
		6	10	

Inner crystals - less energy loss
(4x4)

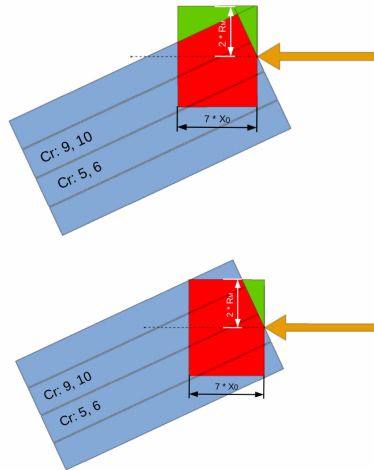
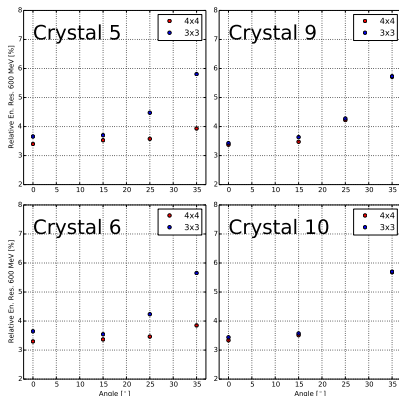


Outer crystals - no difference
between 3x3 and 4x4



Angle Scan - Relative Energy Resolution

Relative energy resolution
as function of incidence angle
at 600 MeV:



Conclusion and Outlook

Conclusion

- Development of standard procedure to determine lowest channel threshold
- Perfect for finding a proper APD gain
- BWEC will have a nice energy resolution at the inner crystal ring. Some losses at outer ring.

Outlook

- Find proper APD gain and FEE att./ampl.
- Go on with analysis:
 - Position scan
 - PANDA ADC
- Preparing beamtime in December in the tagger facility (gammas) at low energies, and tagging pre-shower events with an extra detector